## Search Notes

SEARCHED

Application/Control No.

Applicant(s)/Patent under Reexamination

10/659,568 Examiner CHEN ET AL.
Art Unit
2176

Amelia Rutledge

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMF	
EAST(US-PGPUB, USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB)See Search History Printout.	12/7/2007	AR	
ACM Digital Library search - see search printouts	2/15/2006	AR	
IEEE Xplore database search	2/15/2006	AR	
PALM Inventor Name Search	12/10/2007	AR	

Class Subclass Date		Examiner	
715	512	2/15/2006	AR
715	512	8/2/2006	AR
715	512	10/20/2006	AR
715	512	3/23/2007	AR
715	512	12/7/2007	AR

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examine		
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